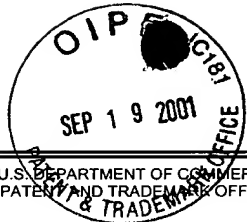


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 203870US6		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenji NAKAGAWA, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>Apr</i>	AO	2000-168896	6/20/00	Japan (w/ English Abstract)			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>A. Thurman</i>					Date Considered <i>9-9-03</i>		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form PTO 1449
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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.
203870US6

SERIAL NO.
09/883,997

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Kenji NAKAGAWA, et al.

FILING DATE
June 20, 2001

GROUP
3723

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
AK	AI	2-162011 ✓	06/21/90	JAPAN (with English Abstracts)		X
AK	AJ	2-206539 ✓	08/16/90	JAPAN (with English Abstracts)		X
AST	AK	4-046638 ✓	02/17/92	JAPAN (with English Abstracts)		X
AST	AL	4-154550 ✓	05/27/92	JAPAN (with English Abstracts)		X
AST	AM	4-253690 ✓	09/09/92	JAPAN (with English Abstracts)		X
AK	AN	4-279497 ✓	10/05/92	JAPAN (with English Abstracts)		X
AK	AO	10-194388 ✓	07/28/98	JAPAN (with English Abstracts)		X
AK	AP	10-194389 ✓	07/28/98	JAPAN (with English Abstracts)		X
AK	AQ	60-230844 ✓	11/16/85	JAPAN (with English Abstracts)		X
AK	AR	62-46434 ✓	10/02/87	JAPAN (with English Abstracts)		X
AST	AS	62-94543 ✓	05/01/87	JAPAN (with English Abstracts)		X
AK	AT	2000-326395 ✓	11/28/2000	JAPAN (with English Abstracts)		X
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

Examiner
A. Thomas

Date Considered
9-9-03

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